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Introduction

This volume contains the papers presented during the 2021 International Conference on Optical Instrument and Technology at the topical meeting of Optoelectronic Imaging/Spectroscopy and Signal Processing Technology. The focus of this meeting is especially directed to the advance in this field and related areas. Owing to the COVID-19 pandemic, this meeting has been postponed for about half a year and was held in an online mode. But we still received 22 submissions from scientists and engineers from China. The strong limitation of the number of papers which can be presented orally and discussed effectively during meeting without holding parallel sessions was an important orientation. The classification of all the accepted papers into the two topical sessions listed above was also very difficult and it often requires compromises. We hope that our decision will be accepted by the audience.

The editors would like to express thanks to the international program committee for helping us to find a good solution to finalize the meeting. We would also like to thank all the authors who spent a lot of time and effort in the preparation of their papers. Our appreciation would also go to Prof. Liquan Dong and Mrs. Cuiling Li, and all the local staff from Beijing Institute of Technology. Without their help, it was not possible to make the meeting so successful.

Guohai Situ
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